

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO. : WOLFRAMM
ET AL-1 PCT09/889759
JC18 Rec'd PCT/PTO 20 JUL 2001

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT: ARIBERT P. WOLFRAMM ET AL

(Use several sheets if necessary)

FILING DATE:

GROUP:

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JLB	AA	5,614,907	03/1997	Kreitmair-Steck et al. (enclosed)			
JLB	AB	5,659,318	08/1997	Madsen et al. (enclosed)			
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
JLB	AF	0 634 668	01/1995	Europe				
	AG	0 757 259	02/1997	Europe				
	AH	39 22 086	10/1990	Germany				
	AI	43 06 920	09/1994	Germany				
JLB	AJ	43 28 573	03/1995	Germany				
	AK							
	AL							
	AM							
	AN							
	AO							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

JLB	AP		Griffiths, H. (1995) "Interferometric Synthetic Aperture Radar", Electronics and Communication Engineering Journal, GB, Institution of Electrical Engineers, London, Vol. 7, pp. 247-256.
JLB	AR		Stefan Buckreuss et al. (1994) "Advanced SAR Interferometry Study", DLR (enclosed)
JLB	AS		Christopher T. Allen (1995) "Interferometric Synthetic Aperture Radar", IEEE Geoscience and Remote Sensing Society Newsletter, pp. 6-13. (enclosed)

EXAMINER

S E. BUCZINSKI

DATE CONSIDERED

21 MAY 02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.